I have refined the last two comments that we had sent in, originally labeled "Batch C". I would like to thank Mr. Nordman, he helped me better translate my thought into comments within the test procedure context. Here they are:

- PoE Source (PSE by IEEE terminology): not applicable to SNE at this time
- PoE using device (PD by IEEE terminology): add note to test procedure to record whether device and power source support LLDP. Consider adder for SNE that do implement LLDP to reflect efficiencies it enables on the power source.
- EEE, general: TP may already or should say that if SNE device supports LLDP, then the connected device(s) should also. The IEEE specification defines what we call PICs for testing this, so I do not think you need to go into the details.
- EEE, on the RX side: Consider adder for SNE that implement LLDP for EEE as the feature allows for enhanced savings in the system. Pls. note that unlike PoE/P, each system has a TX and RX (vs. one side of the link being PD or PSE, here its like having both).

I am happy to provide more detail and/or discuss if you think it's helpful.

Regards,
Wael